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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	37
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 12bit SAR; D/A 12bit
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-TQFP
Supplier Device Package	48-TQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32tg11b120f128gq48-ar

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the following conditions, unless stated otherwise:

- Typical values are based on T_{AMB}=25 °C and V_{DD}= 3.3 V, by production test and/or technology characterization.
- Minimum and maximum values represent the worst conditions across supply voltage, process variation, and operating temperature, unless stated otherwise.

Refer to 4.1.2.1 General Operating Conditions for more details about operational supply and temperature limits.

4.1.1 Absolute Maximum Ratings

Stresses above those listed below may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.1. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Storage temperature range	T_{STG}		-50	—	150	°C
Voltage on any supply pin	V_{DDMAX}		-0.3	—	3.8	V
Voltage ramp rate on any supply pin	$V_{DDRAMPMAX}$		—	—	1	V / µs
DC voltage on any GPIO pin	V_{DIGPIN}	5V tolerant GPIO pins[1 2 3]	-0.3	—	Min of 5.25 and IOVDD +2	V
		LCD pins[3]	-0.3	—	Min of 3.8 and IOVDD +2	V
		Standard GPIO pins	-0.3	—	IOVDD+0.3	V
Total current into VDD power lines	I_{VDDMAX}	Source	—	—	200	mA
Total current into VSS ground lines	I_{VSSMAX}	Sink	—	—	200	mA
Current per I/O pin	I_{IOMAX}	Sink	—	—	50	mA
		Source	—	—	50	mA
Current for all I/O pins	$I_{IOALLMAX}$	Sink	—	—	200	mA
		Source	—	—	200	mA
Junction temperature	T_J	-G grade devices	-40	—	105	°C
		-I grade devices	-40	—	125	°C

Note:

1. When a GPIO pin is routed to the analog module through the APORT, the maximum voltage = IOVDD.
2. Valid for IOVDD in valid operating range or when IOVDD is undriven (high-Z). If IOVDD is connected to a low-impedance source below the valid operating range (e.g. IOVDD shorted to VSS), the pin voltage maximum is IOVDD + 0.3 V, to avoid exceeding the maximum IO current specifications.
3. To operate above the IOVDD supply rail, over-voltage tolerance must be enabled according to the GPIO_Px_OVTDIS register. Pins with over-voltage tolerance disabled have the same limits as Standard GPIO.

4.1.2 Operating Conditions

When assigning supply sources, the following requirements must be observed:

- VREGVDD must be greater than or equal to AVDD, DVDD and all IOVDD supplies.
- VREGVDD = AVDD
- DVDD ≤ AVDD
- IOVDD ≤ AVDD

4.1.10 Flash Memory Characteristics[5]

Table 4.17. Flash Memory Characteristics[5]

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Flash erase cycles before failure	EC_{FLASH}		10000	—	—	cycles
Flash data retention	RET_{FLASH}	T ≤ 85 °C	10	—	—	years
		T ≤ 125 °C	10	—	—	years
Word (32-bit) programming time	t_{W_PROG}	Burst write, 128 words, average time per word	20	26	32	µs
		Single word	59	68	83	µs
Page erase time[4]	t_{PERASE}		20	27	35	ms
Mass erase time[1]	t_{MERASE}		20	27	35	ms
Device erase time[2 3]	t_{DERASE}	T ≤ 85 °C	—	54	70	ms
		T ≤ 125 °C	—	54	75	ms
Erase current[6]	I_{ERASE}	Page Erase	—	—	1.7	mA
		Mass or Device Erase	—	—	2.0	mA
Write current[6]	I_{WRITE}		—	—	3.5	mA
Supply voltage during flash erase and write	V_{FLASH}		1.62	—	3.6	V

Note:

1. Mass erase is issued by the CPU and erases all flash.
2. Device erase is issued over the AAP interface and erases all flash, SRAM, the Lock Bit (LB) page, and the User data page Lock Word (ULW).
3. From setting the DEVICEERASE bit in AAP_CMD to 1 until the ERASEBUSY bit in AAP_STATUS is cleared to 0. Internal setup and hold times for flash control signals are included.
4. From setting the ERASEPAGE bit in MSC_WRITECMD to 1 until the BUSY bit in MSC_STATUS is cleared to 0. Internal setup and hold times for flash control signals are included.
5. Flash data retention information is published in the Quarterly Quality and Reliability Report.
6. Measured at 25 °C.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
ADC clock frequency	f_{ADCCLK}		—	—	16	MHz
Throughput rate	$f_{ADCRATE}$		—	—	1	Msps
Conversion time[1]	$t_{ADCCONV}$	6 bit	—	7	—	cycles
		8 bit	—	9	—	cycles
		12 bit	—	13	—	cycles
Startup time of reference generator and ADC core	$t_{ADCSTART}$	WARMUPMODE[4] = NORMAL	—	—	5	μs
		WARMUPMODE[4] = KEEPIN-STANDBY	—	—	2	μs
		WARMUPMODE[4] = KEEPINSLO-WACC	—	—	1	μs
SNDR at 1Msps and f_{IN} = 10kHz	$SNDR_{ADC}$	Internal reference[7], differential measurement	TBD	67	—	dB
		External reference[6], differential measurement	—	68	—	dB
Spurious-free dynamic range (SFDR)	$SFDR_{ADC}$	1 MSamples/s, 10 kHz full-scale sine wave	—	75	—	dB
Differential non-linearity (DNL)	DNL_{ADC}	12 bit resolution, No missing co-des	TBD	—	TBD	LSB
Integral non-linearity (INL), End point method	INL_{ADC}	12 bit resolution	TBD	—	TBD	LSB
Offset error	$V_{ADCOFFSETERR}$		TBD	0	TBD	LSB
Gain error in ADC	$V_{ADCGAIN}$	Using internal reference	—	-0.2	TBD	%
		Using external reference	—	-1	—	%
Temperature sensor slope	V_{TS_SLOPE}		—	-1.84	—	mV/°C

Note:

1. Derived from ADCCLK.
2. PSRR is referenced to AVDD when ANASW=0 and to DVDD when ANASW=1 in EMU_PWRCTRL.
3. In ADCn_BIASPROG register.
4. In ADCn_CNTL register.
5. The absolute voltage allowed at any ADC input is dictated by the power rail supplied to on-chip circuitry, and may be lower than the effective full scale voltage. All ADC inputs are limited to the ADC supply (AVDD or DVDD depending on EMU_PWRCTRL_ANASW). Any ADC input routed through the APORT will further be limited by the IOVDD supply to the pin.
6. External reference is 1.25 V applied externally to ADCnEXTREFP, with the selection CONF in the SINGLECTRL_REF or SCANCTRL_REF register field and VREFP in the SINGLECTRLX_VREFSEL or SCANCTRLX_VREFSEL field. The differential input range with this configuration is ± 1.25 V.
7. Internal reference option used corresponds to selection 2V5 in the SINGLECTRL_REF or SCANCTRL_REF register field. The differential input range with this configuration is ± 1.25 V. Typical value is characterized using full-scale sine wave input. Minimum value is production-tested using sine wave input at 1.5 dB lower than full scale.

4.1.14 Analog Comparator (ACMP)

Table 4.21. Analog Comparator (ACMP)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input voltage range	V_{ACMPIN}	ACMPVDD = ACMPn_CTRL_PWRSEL [1]	—	—	$V_{ACMPVDD}$	V
Supply voltage	$V_{ACMPVDD}$	BIASPROG[4] ≤ 0x10 or FULL-BIAS[4] = 0	1.8	—	$V_{VREGVDD\_MAX}$	V
		0x10 < BIASPROG[4] ≤ 0x20 and FULLBIAS[4] = 1	2.1	—	$V_{VREGVDD\_MAX}$	V
Active current not including voltage reference[2]	I_{ACMP}	BIASPROG[4] = 1, FULLBIAS[4] = 0	—	50	—	nA
		BIASPROG[4] = 0x10, FULLBIAS[4] = 0	—	306	—	nA
		BIASPROG[4] = 0x02, FULLBIAS[4] = 1	—	6.5	—	µA
		BIASPROG[4] = 0x20, FULLBIAS[4] = 1	—	74	TBD	µA
Current consumption of internal voltage reference[2]	$I_{ACMPREF}$	VLP selected as input using 2.5 V Reference / 4 (0.625 V)	—	50	—	nA
		VLP selected as input using VDD	—	20	—	nA
		VBDIV selected as input using 1.25 V reference / 1	—	4.1	—	µA
		VADIV selected as input using VDD/1	—	2.4	—	µA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Signal to noise and distortion ratio (1 kHz sine wave), Noise band limited to 250 kHz	$SNDR_{DAC}$	500 ksps, single-ended, internal 1.25V reference	—	60.4	—	dB
		500 ksps, single-ended, internal 2.5V reference	—	61.6	—	dB
		500 ksps, single-ended, 3.3V VDD reference	—	64.0	—	dB
		500 ksps, differential, internal 1.25V reference	—	63.3	—	dB
		500 ksps, differential, internal 2.5V reference	—	64.4	—	dB
		500 ksps, differential, 3.3V VDD reference	—	65.8	—	dB
Signal to noise and distortion ratio (1 kHz sine wave), Noise band limited to 22 kHz	$SNDR_{DAC\_BAND}$	500 ksps, single-ended, internal 1.25V reference	—	65.3	—	dB
		500 ksps, single-ended, internal 2.5V reference	—	66.7	—	dB
		500 ksps, differential, 3.3V VDD reference	—	68.5	—	dB
		500 ksps, differential, internal 1.25V reference	—	67.8	—	dB
		500 ksps, differential, internal 2.5V reference	—	69.0	—	dB
		500 ksps, single-ended, 3.3V VDD reference	—	70.0	—	dB
Total harmonic distortion	THD		—	70.2	—	dB
Differential non-linearity[3]	DNL_{DAC}		TBD	—	TBD	LSB
Intergral non-linearity	INL_{DAC}		TBD	—	TBD	LSB
Offset error[5]	V_{OFFSET}	T = 25 °C	TBD	—	TBD	mV
		Across operating temperature range	TBD	—	TBD	mV
Gain error[5]	V_{GAIN}	T = 25 °C, Low-noise internal reference (REFSEL = 1V25LN or 2V5LN)	TBD	—	TBD	%
		Across operating temperature range, Low-noise internal reference (REFSEL = 1V25LN or 2V5LN)	TBD	—	TBD	%
External load capactiance, OUTSCALE=0	C_{LOAD}		—	—	75	pF

4.1.17 Operational Amplifier (OPAMP)

Unless otherwise indicated, specified conditions are: Non-inverting input configuration, VDD = 3.3 V, DRIVESTRENGTH = 2, MAIN-OUTEN = 1, C_{LOAD} = 75 pF with OUTSCALE = 0, or C_{LOAD} = 37.5 pF with OUTSCALE = 1. Unit gain buffer and 3X-gain connection as specified in table footnotes[8] [1].

Table 4.24. Operational Amplifier (OPAMP)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply voltage (from AVDD)	V_{OPA}	HCMDIS = 0, Rail-to-rail input range	2	—	3.8	V
		HCMDIS = 1	1.62	—	3.8	V
Input voltage	V_{IN}	HCMDIS = 0, Rail-to-rail input range	V_{VSS}	—	V_{OPA}	V
		HCMDIS = 1	V_{VSS}	—	V_{OPA}-1.2	V
Input impedance	R_{IN}		100	—	—	MΩ
Output voltage	V_{OUT}		V_{VSS}	—	V_{OPA}	V
Load capacitance[2]	C_{LOAD}	OUTSCALE = 0	—	—	75	pF
		OUTSCALE = 1	—	—	37.5	pF
Output impedance	R_{OUT}	DRIVESTRENGTH = 2 or 3, 0.4 V ≤ V_{OUT} ≤ V_{OPA} - 0.4 V, -8 mA < I_{OUT} < 8 mA, Buffer connection, Full supply range	—	0.25	—	Ω
		DRIVESTRENGTH = 0 or 1, 0.4 V ≤ V_{OUT} ≤ V_{OPA} - 0.4 V, -400 µA < I_{OUT} < 400 µA, Buffer connection, Full supply range	—	0.6	—	Ω
		DRIVESTRENGTH = 2 or 3, 0.1 V ≤ V_{OUT} ≤ V_{OPA} - 0.1 V, -2 mA < I_{OUT} < 2 mA, Buffer connection, Full supply range	—	0.4	—	Ω
		DRIVESTRENGTH = 0 or 1, 0.1 V ≤ V_{OUT} ≤ V_{OPA} - 0.1 V, -100 µA < I_{OUT} < 100 µA, Buffer connection, Full supply range	—	1	—	Ω
Internal closed-loop gain	G_{CL}	Buffer connection	TBD	1	TBD	-
		3x Gain connection	TBD	2.99	TBD	-
		16x Gain connection	TBD	15.7	TBD	-
Active current[4]	I_{OPA}	DRIVESTRENGTH = 3, OUT-SCALE = 0	—	580	—	µA
		DRIVESTRENGTH = 2, OUT-SCALE = 0	—	176	—	µA
		DRIVESTRENGTH = 1, OUT-SCALE = 0	—	13	—	µA
		DRIVESTRENGTH = 0, OUT-SCALE = 0	—	4.7	—	µA

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PC4	13	GPIO	PC5	14	GPIO
PB7	15	GPIO	PB8	16	GPIO
PA8	17	GPIO	PA9	18	GPIO
PA10	19	GPIO	RESETn	20	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
PB11	21	GPIO	AVDD	23 27	Analog power supply.
PB13	24	GPIO	PB14	25	GPIO
PD0	28	GPIO (5V)	PD1	29	GPIO
PD2	30	GPIO (5V)	PD3	31	GPIO
PD4	32	GPIO	PD5	33	GPIO
PD6	34	GPIO	PD7	35	GPIO
PD8	36	GPIO	PC6	37	GPIO
PC7	38	GPIO	DVDD	39	Digital power supply.
DECOUPLE	40	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PC8	41	GPIO
PC9	42	GPIO	PC10	43	GPIO (5V)
PC11	44	GPIO (5V)	PC12	45	GPIO (5V)
PC13	46	GPIO (5V)	PC14	47	GPIO (5V)
PC15	48	GPIO (5V)	PF0	49	GPIO (5V)
PF1	50	GPIO (5V)	PF2	51	GPIO
PF3	52	GPIO	PF4	53	GPIO
PF5	54	GPIO	PE8	57	GPIO
PE9	58	GPIO	PE10	59	GPIO
PE11	60	GPIO	PE12	61	GPIO
PE13	62	GPIO	PE14	63	GPIO
PE15	64	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PB8	11	GPIO	PA8	12	GPIO
PA12	13	GPIO	PA14	14	GPIO
RESETn	15	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.	PB11	16	GPIO
AVDD	18 22	Analog power supply.	PB13	19	GPIO
PB14	20	GPIO	PD4	23	GPIO
PD5	24	GPIO	PD6	25	GPIO
PD7	26	GPIO	PD8	27	GPIO
VREGVSS	28	Voltage regulator VSS	VREGSW	29	DCDC regulator switching node
VREGVDD	30	Voltage regulator VDD input	DVDD	31	Digital power supply.
DECOUPLE	32	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PE4	33	GPIO
PE5	34	GPIO	PE6	35	GPIO
PE7	36	GPIO	PF0	37	GPIO (5V)
PF1	38	GPIO (5V)	PF2	39	GPIO
PF3	40	GPIO	PF4	41	GPIO
PF5	42	GPIO	PE10	45	GPIO
PE11	46	GPIO	PE12	47	GPIO
PE13	48	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

5.14 GPIO Functionality Table

A wide selection of alternate functionality is available for multiplexing to various pins. The following table shows the name of each GPIO pin, followed by the functionality available on that pin. Refer to 5.15 Alternate Functionality Overview for a list of GPIO locations available for each function.

Table 5.14. GPIO Functionality Table

GPIO Name	Pin Alternate Functionality / Description			
	Analog	Timers	Communication	Other
PA0	BUSBY BUSAX LCD_SEG13	TIM0_CC0 #0 TIM0_CC1 #7 PCNT0_S0IN #4	US1_RX #5 US3_TX #0 LEU0_RX #4 I2C0_SDA #0	CMU_CLK2 #0 PRS_CH0 #0 PRS_CH3 #3 GPIO_EM4WU0
PA1	BUSAY BUSBX LCD_SEG14	TIM0_CC0 #7 TIM0_CC1 #0 PCNT0_S1IN #4	US3_RX #0 I2C0_SCL #0	CMU_CLK1 #0 PRS_CH1 #0
PA2	BUSBY BUSAX LCD_SEG15	TIM0_CC2 #0	US1_RX #6 US3_CLK #0	CMU_CLK0 #0
PA3	BUSAY BUSBX LCD_SEG16	TIM0_CDTI0 #0	US3_CS #0 U0_TX #2	CMU_CLK2 #1 CMU_CLK2 #4 CMU_CLKI0 #1 LES_ALTEX2
PA4	BUSBY BUSAX LCD_SEG17	TIM0_CDTI1 #0	US3_CTS #0 U0_RX #2	LES_ALTEX3
PA5	BUSAY BUSBX LCD_SEG18	TIM0_CDTI2 #0	US3_RTS #0 U0_CTS #2	LES_ALTEX4 ACMP1_O #7
PA6	BUSBY BUSAX LCD_SEG19	WTIM0_CC0 #1	U0_RTS #2	PRS_CH6 #0 ACMP0_O #4 GPIO_EM4WU1
PB3	BUSAY BUSBX LCD_SEG20 / LCD_COM4	TIM1_CC3 #2 WTIM0_CC0 #6	US2_TX #1 US3_TX #2	ACMP0_O #7
PB4	BUSBY BUSAX LCD_SEG21 / LCD_COM5	WTIM0_CC1 #6	US2_RX #1	
PB5	BUSAY BUSBX LCD_SEG22 / LCD_COM6	WTIM0_CC2 #6 PCNT0_S0IN #6	US0_RTS #4 US2_CLK #1	
PB6	BUSBY BUSAX LCD_SEG23 / LCD_COM7	TIM0_CC0 #3 PCNT0_S1IN #6	US0_CTS #4 US2_CS #1	
PC0	VDAC0_OUT0ALT / OPA0_OUTALT #0 BUSACMP0Y BUSACMP0X	TIM0_CC1 #3 PCNT0_S0IN #2	CAN0_RX #0 US0_TX #5 US1_TX #0 US1_CS #4 US2_RTS #0 US3_CS #3 I2C0_SDA #4	LES_CH0 PRS_CH2 #0
PC1	VDAC0_OUT0ALT / OPA0_OUTALT #1 BUSACMP0Y BUSACMP0X	TIM0_CC2 #3 WTIM0_CC0 #7 PCNT0_S1IN #2	CAN0_TX #0 US0_RX #5 US1_TX #4 US1_RX #0 US2_CTS #0 US3_RTS #1 I2C0_SCL #4	LES_CH1 PRS_CH3 #0
PC2	VDAC0_OUT0ALT / OPA0_OUTALT #2 BUSACMP0Y BUSACMP0X	TIM0_CDTI0 #3 WTIM0_CC1 #7	US1_RX #4 US2_TX #0	LES_CH2
PC3	VDAC0_OUT0ALT / OPA0_OUTALT #3 BUSACMP0Y BUSACMP0X	TIM0_CDTI1 #3 WTIM0_CC2 #7	US1_CLK #4 US2_RX #0	LES_CH3

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
U0_TX	2: PA3 3: PC14	4: PC4 5: PF1 6: PD7	UART0 Transmit output. Also used as receive input in half duplex communication.
US0_CLK	0: PE12 1: PE5 2: PC9 3: PC15	4: PB13 5: PA12	USART0 clock input / output.
US0_CS	0: PE13 1: PE4 2: PC8 3: PC14	4: PB14 5: PA13	USART0 chip select input / output.
US0_CTS	0: PE14 2: PC7 3: PC13	4: PB6 5: PB11	USART0 Clear To Send hardware flow control input.
US0_RTS	0: PE15 2: PC6 3: PC12	4: PB5 5: PD6	USART0 Request To Send hardware flow control output.
US0_RX	0: PE11 1: PE6 2: PC10 3: PE12	4: PB8 5: PC1	USART0 Asynchronous Receive. USART0 Synchronous mode Master Input / Slave Output (MISO).
US0_TX	0: PE10 1: PE7 2: PC11 3: PE13	4: PB7 5: PC0	USART0 Asynchronous Transmit. Also used as receive input in half duplex communication. USART0 Synchronous mode Master Output / Slave Input (MOSI).
US1_CLK	0: PB7 1: PD2 2: PF0 3: PC15	4: PC3 5: PB11 6: PE5	USART1 clock input / output.
US1_CS	0: PB8 1: PD3 2: PF1 3: PC14	4: PC0 5: PE4	USART1 chip select input / output.
US1_CTS	1: PD4 2: PF3 3: PC6	4: PC12 5: PB13	USART1 Clear To Send hardware flow control input.
US1_RTS	1: PD5 2: PF4 3: PC7	4: PC13 5: PB14	USART1 Request To Send hardware flow control output.
US1_RX	0: PC1 1: PD1 2: PD6	4: PC2 5: PA0 6: PA2	USART1 Asynchronous Receive. USART1 Synchronous mode Master Input / Slave Output (MISO).
US1_TX	0: PC0 1: PD0 2: PD7	4: PC1 5: PF2 6: PA14	USART1 Asynchronous Transmit. Also used as receive input in half duplex communication. USART1 Synchronous mode Master Output / Slave Input (MOSI).

Table 7.2. QFN80 PCB Land Pattern Dimensions

Dimension	Typ
C1	8.90
C2	8.90
E	0.40
X1	0.20
Y1	0.85
X2	7.30
Y2	7.30

Note:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm.
4. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.
5. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
6. The stencil thickness should be 0.125 mm (5 mils).
7. The ratio of stencil aperture to land pad size can be 1:1 for all pads.
8. A 3x3 array of 1.45 mm square openings on a 2.00 mm pitch can be used for the center ground pad.
9. A No-Clean, Type-3 solder paste is recommended.
10. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

Table 9.1. QFN64 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	—	0.05
b	0.20	0.25	0.30
A3	0.203 REF		
D	9.00 BSC		
e	0.50 BSC		
E	9.00 BSC		
D2	7.10	7.20	7.30
E2	7.10	7.20	7.30
L	0.40	0.45	0.50
L1	0.00	—	0.10
aaa	0.10		
bbb	0.10		
ccc	0.10		
ddd	0.05		
eee	0.08		

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

Table 9.2. QFN64 PCB Land Pattern Dimensions

Dimension	Typ
C1	8.90
C2	8.90
E	0.50
X1	0.30
Y1	0.85
X2	7.30
Y2	7.30

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm.
4. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
5. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
6. The stencil thickness should be 0.125 mm (5 mils).
7. The ratio of stencil aperture to land pad size can be 1:1 for all pads.
8. A 3x3 array of 1.45 mm square openings on a 2.00 mm pitch can be used for the center ground pad.
9. A No-Clean, Type-3 solder paste is recommended.
10. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.3 QFN64 Package Marking

Figure 9.3. QFN64 Package Marking

The package marking consists of:

- PPPPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code. The first letter is the device revision.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.

10.3 TQFP48 Package Marking

Figure 10.3. TQFP48 Package Marking

The package marking consists of:

- PPPPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code. The first letter is the device revision.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.

11.2 QFN32 PCB Land Pattern

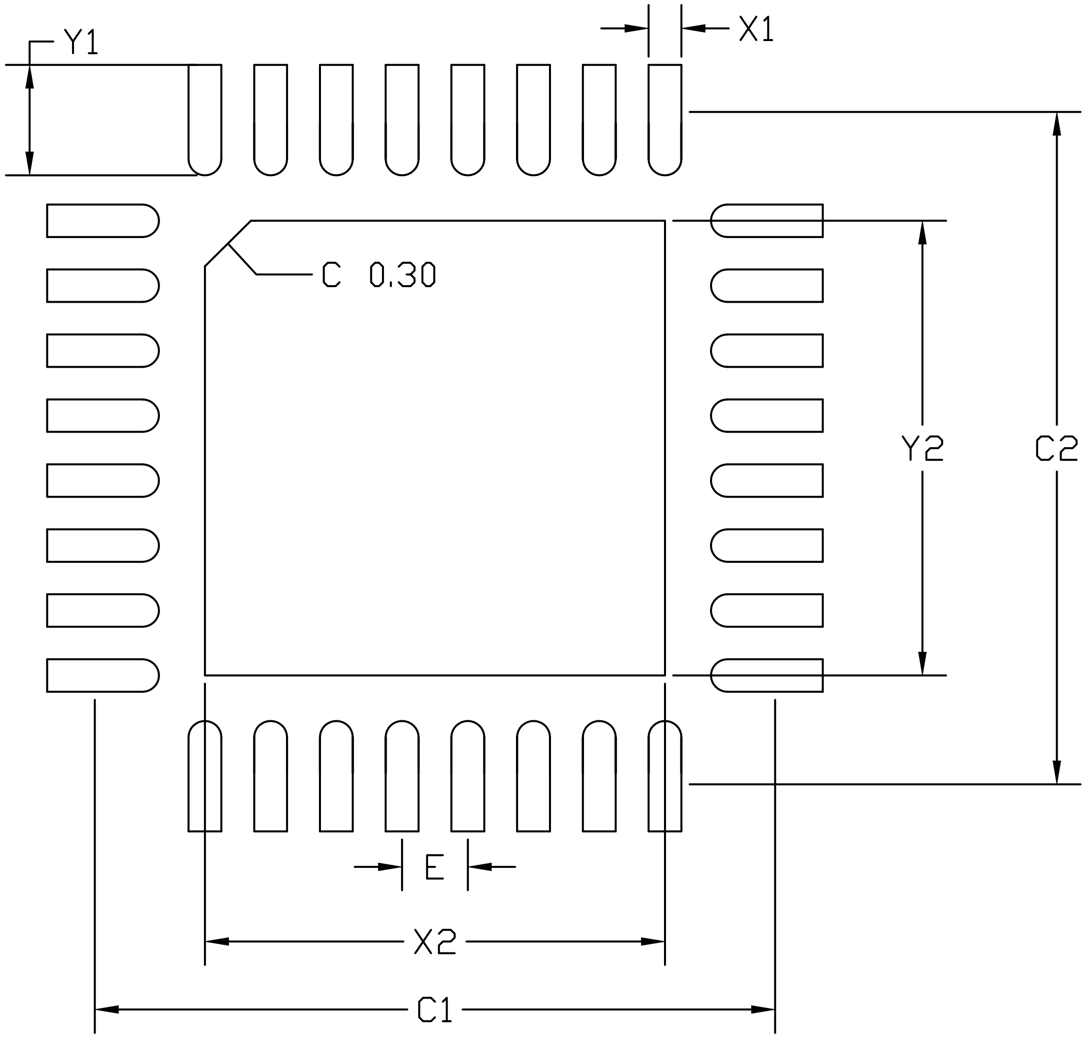


Figure 11.2. QFN32 PCB Land Pattern Drawing

Table 11.2. QFN32 PCB Land Pattern Dimensions

Dimension	Typ
C1	5.00
C2	5.00
E	0.50
X1	0.30
Y1	0.80
X2	3.80
Y2	3.80

Note:

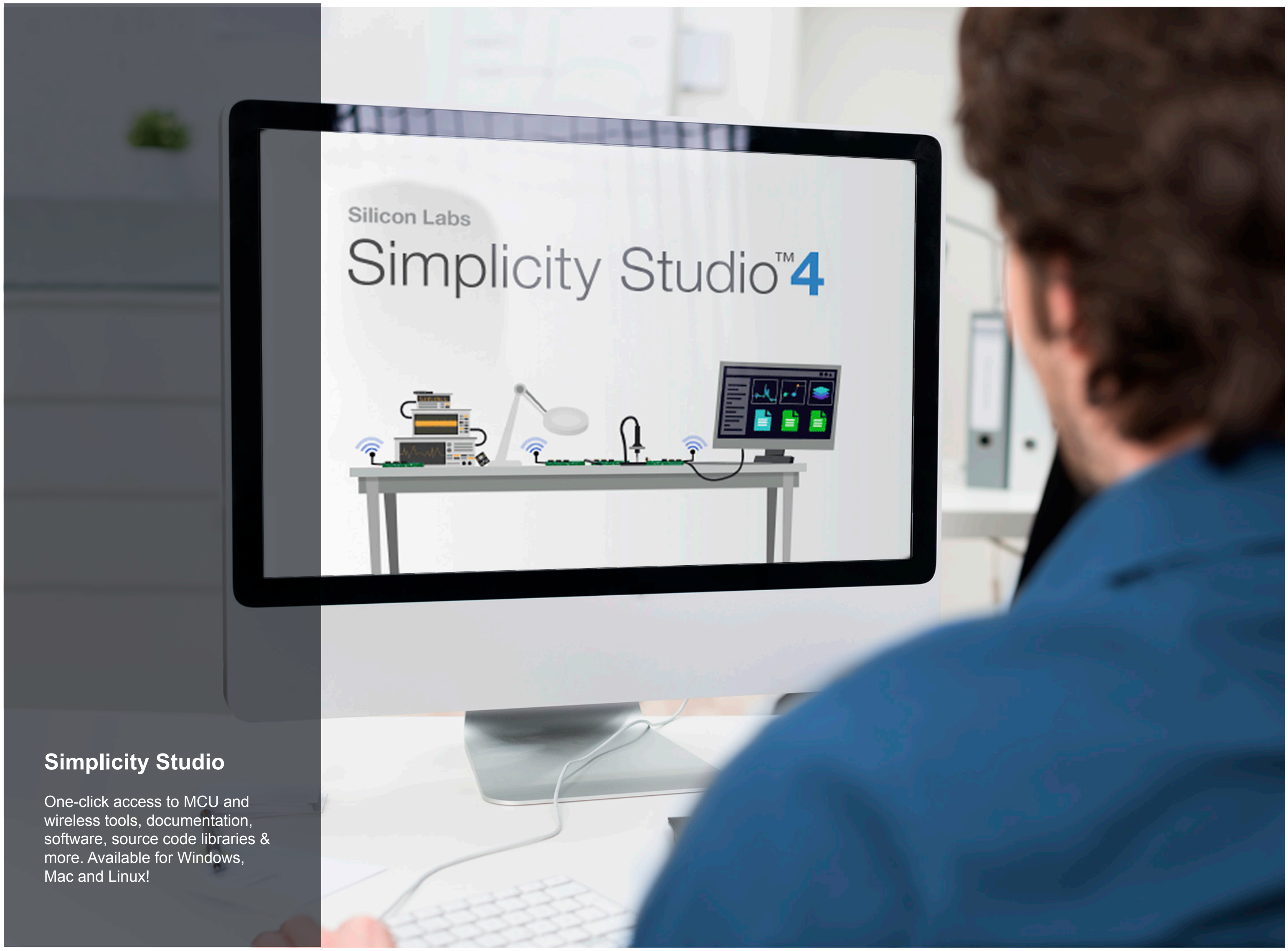
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size can be 1:1 for all perimeter pads.
7. A 2x2 array of 0.9 mm square openings on a 1.2 mm pitch should be used for the center ground pad.
8. A No-Clean, Type-3 solder paste is recommended.
9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11.3 QFN32 Package Marking

Figure 11.3. QFN32 Package Marking

The package marking consists of:

- PPPPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code. The first letter is the device revision.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.



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